Certificate of Test

dq. 1851, Republic of Norea (Tel: +22-31-323-6070 / Fax: +82-31-323-6071) Page (1) / (52) 1. Client Name : IDRO Co.,Ltd Address : 219, 17, (ACC Guangkyo Tower1), 17, Daehak 4-ro, Yeongtong-gu, Suvon-si, Gyeonggi-do, Republic of Korea Date of Receipt : 2021-11-12 1. Start Sample Description / Model : RFID Module / IDRO900ME-M FCC ID : XVY-IDRO900ME-M 9. Date of Test : ■ Fixed test □ Field test (Address:211-71, Geumgok-ro, Hwaseong-si, Gyeonggi-do, 18511, Republic of Korea) 9. Date of Test : ■ Fixed test □ Field test (Address:211-71, Geumgok-ro, Hwaseong-si, Gyeonggi-do, 18511, Republic of Korea) 9. Date of Test : ■ Fixed test □ Field test (Address:211-71, Geumgok-ro, Hwaseong-si, Gyeonggi-do, 18511, Republic of Korea) 9. Date of Test : ■ 2021-12-03 ~ 2021-12-10 6. Test method used : FCC Part 15 Subpart C 15.247 7. Testing Environment : Temperature: (25 ± 5) °C, Humidity: Less than 75 % R.H. * Unless specified otherwise in the individual methods, the tests were conducted on ambient conditions. 1. Test Results : Refer to the test results The results shown in this test report information and RRA designation. Mfirmation Tested by Jong-Myoung, Shin		Hwaseong-si, Gyeonggi-	Report No.: NW2112-F00	5-1	66	
 Name : IDRO Co.,Ltd Address : 219, 17, (ACE Guangkyo Tower1), 17, Daehak 4-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, Republic of Korea Date of Receipt : 2021-11-12 Use of Report : FCC Approval Test Sample Description / Model : RFID Module / IDRO900ME-M FCC ID : XVY-IDRO900ME-M Place of Test : = Fixed test = Field test (Address:211-71, Geumgok-ro, Hwaseong-si, Gyeonggi-do, 18511, Republic of Korea) Date of Test : 2021-12-03 ~ 2021-12-10 Test method used : FCC Part 15 Subpart C 15.247 Testing Environment: Temperature: (25 ± 5) °C, Humidity: Less than 75 % R.H. * Unless specified otherwise in the individual methods, the tests were conducted on ambient conditions. Test Results : Refer to the test results The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This Test Report cannot be reproduced, except in full This test report is not related to KOLAS recognition and RRA designation. Affirmation Tested by Jong-Myoung, Shin Affirmation Tested State Comparison of the sample(s) tested unless otherwise state. 	do, 18511, Republic o	f Korea	Page (1) / (52)		Your husiness' success start	s with NCT
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NCT CO., LTD.					Dec 21, 20)21
Contact us at report@nct.re.kr to confirm the authenticity of this report						



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APPENDIX

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1. General Information's <u>1.1 Test Performed</u>

Laboratory	:	NCT Co., Ltd.
Address	:	211-71, Geumgok-ro, Hwaseong-si, Gyeonggi-do, 18511, Korea
Telephone	:	+82-31-323-6070
Facsimile	:	+82-31-323-6071
FCC Designation No.	:	KR0166
FCC Registration Number	:	409631

2. Information's about Test Item

2.1 Applicant Information

Company name	:	IDRO Co.,Ltd
Address		219, 17, (ACE Guangkyo Tower1), 17, Daehak 4-ro, Yeongtong-gu,
Address	•	Suwon-si, Gyeonggi-do, Republic of Korea
Telephone / Facsimile	:	+82-31-225-7883 / +82-31-225-7886

2.2 Equipment Under Test (EUT) description

Test item particulars	:	RFID Module
Model and/or type reference	:	IDRO900ME-M
Additional model name	:	-
Serial number	:	Prototype
Antenna type and gain	:	Circular microstrip patch antenna (M/N: IDRO260-915) Max Gain 5.84 dBi
Date (s) of performance of tests:	:	2021-12-03 ~ 2021-12-10
Date of receipt of test item	:	2021-11-12
EUT condition	:	Pre-production, not damaged
Number of channel	:	50
EUT Power Source	:	DC 4.0 V
Type of Modulation	:	A1D
Firmware version	:	1.0
Hardware version	:	1.0
Test software name(version)	:	E710Tester



2.3 Tested Frequency

Test Mode	Test frequency (M脸)			
Test Mode	Low frequency	Middle frequency	High frequency	
RFID (900 № FHSS)	902.75	914.75	927.25	



3. Test Report

3.1 Test Summary

Applied	Test Items	Clause	Test Condition	Result
\boxtimes	Antenna Requirement	15.203		С
\boxtimes	20 dB Bandwidth	15.247(a)		С
\boxtimes	Number of Hopping Frequencies	15.247(a)		С
\boxtimes	Time of Occupancy (Dwell Time)	15.247(a)	Conducted	С
\boxtimes	Carrier Frequencies Separation	15.247(a)		С
\boxtimes	Peak Output Power	15.247(b)		С
\boxtimes	Conducted Spurious Emission	15.247(d)		С
\boxtimes	Radiated Spurious Emission	15.247(d) 15.205 & 15.209	Radiated	С
	Conducted Emissions	15.207	AC Line Conducted	C ^{note2}

<u>Note 1</u>: C=Complies NC=Not Complies NT=Not Tested NA=Not Applicable

Note 2: This product is only using DC power. So, AC conducted emission test has not been performed.

Note 3: This test item was performed in each axis and the worst case data was reported.

The sample was tested according to the following specification: ANSI C63.10:2013

Compliance was determined by specification limits of the applicable standard according to customer requirements.



3.2 Test Report Version

Test Report No.	Date	Description
NW2111-F005	2021-12-15	Initial issue
NW2111-F005-1	2021-12-21	Added the Annex III (Uncertainty)



3.3 Transmitter Requirements

3.3.1 Antenna Requirement

Accoding to §15.203 An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section. The manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.

Accoding to \$15.247(b)(4) e conducted output power limit specified in paragraph (b) of this section is based on the use of antennas with directional gains that do not exceed 6 dBi. Except as shown in paragraph (c) of this section, if transmitting antennas of directional gain greater than 6 dBi are used, the conducted output power from the intentional radiator shall be reduced below the stated values in paragraphs (b)(1), (b)(2), and (b)(3) of this section, as appropriate, by the amount in dB that the directional gain of the antenna exceeds 6 dBi.

3.3.1.1 Result

Complies

(The transmitter has a Circular microstrip patch antenna. The directional peak gain of the antenna is 5.84 dBi.)



3.3.2 20 dB Bandwidth

3.3.2.1 Test Setup

Refer to the APPENDIX I.

3.3.2.2 Limit

For frequency hopping systems operating in the 902-928 MHz band: if the 20 dB bandwidth of the hopping channel is less than 250 kHz, the system shall use at least 50 hopping frequencies and the average time of occupancy on any frequency shall not be greater than 0.4 seconds within a 20 second period; if the 20 dB bandwidth of the hopping channel is 250 kHz or greater, the system shall use at least 25 hopping frequencies and the average time of occupancy on any frequency on any frequency shall not be greater than 0.4 seconds within a 10 second period. The maximum allowed 20 dB bandwidth of the hopping channel is 500 kHz.

3.3.2.3 Test Procedure

- 1. The 20 dB bandwidth were measured with a spectrum analyzer connected to RF antenna Connector (conducted measurement) while EUT was operating in transmit mode. The analyzer center frequency was set to the EUT carrier frequency, using the analyzer.
- 2. The bandwidth of the fundamental frequency was measured with the spectrum analyzer using below setting:

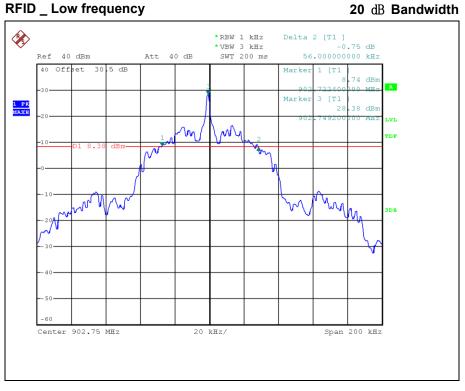
 $\begin{array}{l} \mathsf{RBW} = 1\% \text{ to } 5\% \text{ of the } 20 \ \mathrm{dB} \ \mathsf{BW} \\ \mathsf{VBW} \geq 3 \times \mathsf{RBW} \\ \mathsf{Span} = \mathsf{between} \ \mathsf{two} \ \mathsf{times} \ \mathsf{and} \ \mathsf{five} \ \mathsf{times} \ \mathsf{the} \ 20 \ \mathrm{dB} \ \mathsf{bandwidth} \\ \mathsf{Sweep} = \mathsf{Auto} \\ \mathsf{Detector} = \mathsf{Peak} \\ \mathsf{Trace} = \mathsf{Max} \ \mathsf{hold} \end{array}$

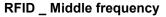
3.3.2.4 Test Result

Test Mode	Test Frequency	20 ^{dB} Bandwidth (KHz)
RFID	Low	56.00
	Middle	52.40
	High	60.71

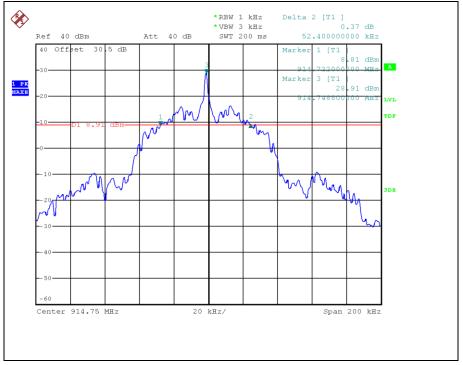


3.3.2.5 Test Plot



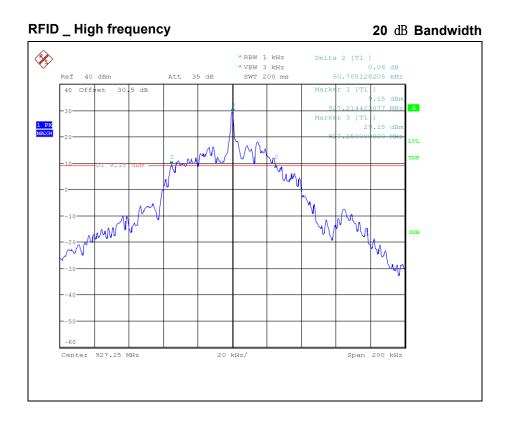






Test Repot No.: NW2112-F005-1







3.3.3 Number of Hopping Frequencies

3.3.3.1 Test Setup

Refer to the APPENDIX I.

3.3.3.2 Limit

Limit : >= 50 hops

3.3.3.3 Test Procedure

The number of hopping frequencies was measured with a spectrum analyzer connected to the antenna terminal, while EUT had its hopping function enabled.

To get higher resolution, two frequency ranges for FH mode within the 902 ~ 928 Mb were examined.

The spectrum analyzer is set to:

Span = 30 Mz

RBW = To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller.

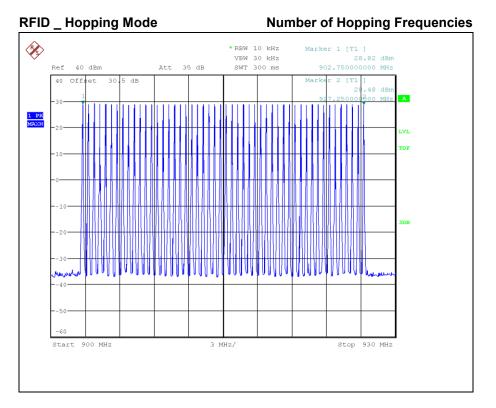
$VBW \geq RBW$	Sweep = Auto
Detector = Peak	Trace = Max hold

3.3.3.4 Test Result

Test Mode	Number of Hopping Channels
RFID	50



3.3.3.5 Test Plot





3.3.4 Time of Occupancy (Dwell Time)

3.3.4.1 Test Setup

Refer to the APPENDIX I.

3.3.4.2 Limit

For frequency hopping systems operating in the 902-928 MHz band: if the 20 dB bandwidth of the hopping channel is less than 250 kHz, the system shall use at least 50 hopping frequencies and the average time of occupancy on any frequency shall not be greater than 0.4 seconds within a 20 second period; if the 20 dB bandwidth of the hopping channel is 250 kHz or greater, the system shall use at least 25 hopping frequencies and the average time of occupancy on any frequency shall not be greater than 0.4 seconds within a 10 second period. The maximum allowed 20 dB bandwidth of the hopping channel is 500 kHz.

3.3.4.3 Test Procedure

The dwell time was measured with a spectrum analyzer connected to the antenna terminal, while EUT had its hopping function enabled.

The spectrum analyzer is set to:

 Center frequency = 914.75 №
 Span = Zero

 RBW = 100 KHz (RBW shall be ≤ channel spacing and where possible RBW should be set >> 1 / T, where T is the expected dwell time per channel)

 VBW ≥ RBW
 Detector = Peak

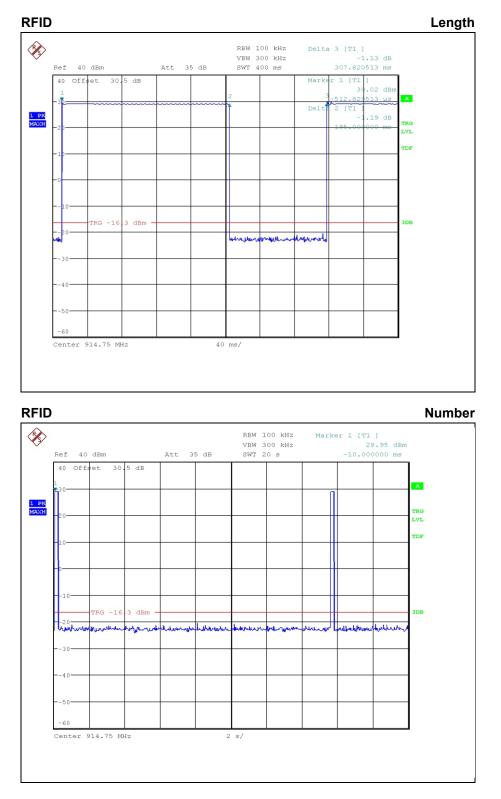
 Trace = Max hold

3.3.4.4 Test Result

Test Frequency	Length	Number	Dwell Time		
(₩z)	(ms)		(ms)		
914.75	195.00	2	390.00		



3.3.4.5 Test Plot



Test Repot No.: NW2112-F005-1



3.3.5 Carrier Frequencies Separation

3.3.5.1 Test Setup

Refer to the APPENDIX I.

3.3.5.2 Limit

Limit : \geq 25 KHz or \geq 20 dB BW whichever is greater.

3.3.5.3 Test Procedure

The carrier frequency separation was measured with a spectrum analyzer connected to the antenna terminal, while EUT had its hopping function enabled.

After the trace being stable, the reading value between the peaks of the adjacent channels using the marker delta function was recorded as the measurement results.

The spectrum analyzer is set to:

Span = wide enough to capture the peaks of two adjacent channels

RBW = Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel.

VBW ≥ RBW	Sweep = Auto
Detector = Peak	Trace = Max hold

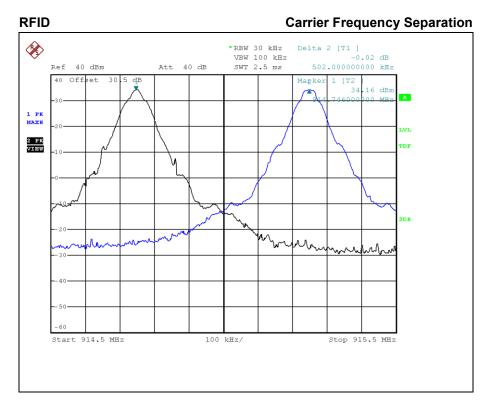
3.3.5.4 Test Result

Test Mode	Carrier Frequencies Separation (KHz)	Min. Limit (KHz)
RFID	502.00	52.40

Note: Limit(KHz) = Test Result of 20 dB BW



3.3.5.5 Test Plot





3.3.6 Peak Output Power

3.3.6.1 Test Setup

Refer to the APPENDIX I.

3.3.6.2 Limit

The maximum peak output power of the intentional radiator shall not exceed the following:

1. §15.247(b)(2), For frequency hopping systems operating in the 902-928 MHz band: 1 watt for systems employing at least 50 hopping channels; and, 0.25 watts for systems employing less than 50 hopping channels, but at least 25 hopping channels, as permitted under paragraph (a)(1)(i) of this section.

3.3.6.3 Test Procedure

- 1. The RF output power was measured with a spectrum analyzer connected to the RF Antenna connector (conducted measurement) while EUT was operating in transmit mode at the appropriate center frequency, a spectrum analyzer was used to record the shape of the transmit signal.
- 2. The peak output power of the fundamental frequency was measured with the spectrum analyzer using; Span = approximately 5 times of the 20 dB bandwidth, centered on a hopping channel

 $\begin{array}{ll} \mathsf{RBW} \ \geq \ \mathsf{20} \ \mathrm{dB} \ \mathsf{BW} \\ \mathsf{VBW} \ \geq \ \mathsf{RBW} \\ \mathsf{Sweep} = \mathsf{Auto} \\ \mathsf{Detector} \ \mathsf{function} = \mathsf{Peak} \\ \mathsf{Trace} = \mathsf{Max} \ \mathsf{hold} \end{array}$

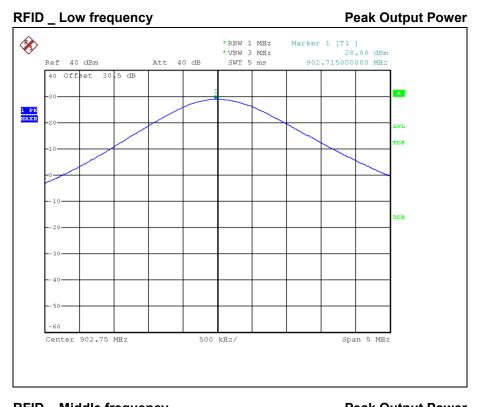
3.3.6.4 Test Result

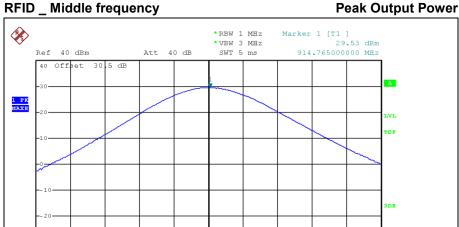
Test Mode	Toot Executorov	Peak Out	put Power	Frame Average Power		
Test Mode	Test Frequency	dB m	mW	dB m	mW	
	Low	28.88	772.68	28.03	635.33	
RFID	Middle	29.53	897.43	28.04	636.80	
	High	28.92	779.83	28.00	630.96	

Note1: Frame Average Power was tested using an average power meter for reference only.



3.3.6.5 Test Plot





Test Repot No.: NW2112-F005-1

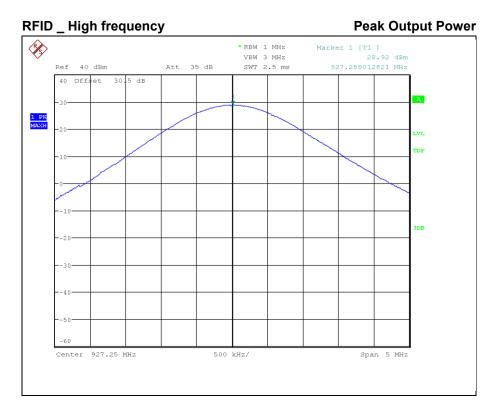
Span 5 MHz

500 kHz/

-60

Center 914.75 MHz







3.3.7 TX Radiated Spurious Emission and Conducted Spurious Emission

3.3.7.1 Test Setup

Refer to the APPENDIX I.

3.3.7.2 Limit

According to \$15.247(d), in any 100 KHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 KHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph(b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in section \$15.209(a) is not required. In addition, radiated emission which in the restricted band, as define in section \$15.205(a), must also comply the radiated emission limits specified in section \$15.209(a) (see section \$15.205(c))

According to § 15.209(a), except as provided elsewhere in this Subpart, the emissions from an intentional radiator shall not exceed the field strength levels specified in the following table

Frequency (MHz)	Limit (uV/m)	Measurement Distance (meter)
0.009 ~ 0.490	2400/F (KHz)	300
0.490 ~ 1705	24000/F (KHz)	30
1705 ~ 30.0	30	30
30 ~ 88	100 **	3
88 ~ 216	150 **	3
216 ~ 960	200 **	3
Above 960	500	3

** Except as provided in 15.209(g), fundamental emissions from intentional radiators operating under this Section shall not be located in the frequency bands 54 - 72 Mb, 76 - 88 Mb, 174 - 216 Mb or 470 - 806 Mb. However, operation within these frequency bands is permitted under other sections of this Part, e.g. 15.231 and 15.241.



According to § 15.205(a) and (b), only spurious emissions are permitted in any of the frequency bands listed below:

MHz	MHz	MHz	GHz
0.009 ~ 0.110	16.42 ~ 16.423	399.90 ~ 410	4.5 ~ 5.15
0.495 ~ 0.505	16.69475 ~ 16.69525	608 ~ 614	5.35 ~ 5.46
2.1735 ~ 2.1905	16.80425 ~ 16.80475	960 ~ 1240	7.25 ~ 7.75
4.125 ~ 4.128	25.5 ~ 25.67	1300 ~ 1427	8.025 ~ 8.5
4.17725 ~ 4.17775	37.5 ~ 38.	1435 ~ 1626.5	9.0 ~ 9.2
4.20725 ~ 4.20775	25 73 ~ 74.6	1645.5 ~ 1646.5	9.3 ~ 9.5
4.17725 ~ 4.17775	74.8 ~ 75.2	1660 ~ 1710	10.6 ~ 12.7
6.215 ~ 6.218	108 ~ 121.94	1718.8 ~ 1722.2	13.25 ~ 13.4
6.26775 ~ 6.26825	149.9 ~ 150.05	2200 ~ 2300	14.47 ~ 14.5
6.31175 ~ 6.31225	156.52475 ~ 156.52525	2310 ~ 2390	15.35 ~ 16.2
8.291 ~ 8.294	156.7 ~ 156.9	2483.5 ~ 2500	17.7 ~ 21.4
8.362 ~ 8.366	162.0125 ~ 167.17	2690 ~ 2900	22.01 ~ 23.12
8.37625 ~ 8.38675	3345.8 ~ 3358	3260 ~ 3267	23.6 ~ 24.0
8.41425 ~ 8.41475	3600 ~ 4400	3332 ~ 3339	31.2 ~ 31.8
12.51975 ~ 12.52025	3345.8 ~ 3358	240 ~ 285	36.43 ~ 36.5
12.57675 ~ 12.57725	3600 ~ 4400	322 ~ 335.4	Above 38.6
13.36 ~ 13.41			

The field strength of emissions appearing within these frequency bands shall not exceed the limits shown in §15.209. At frequencies equal to or less than 1000 Mb, compliance with the limits in §15.209 shall be demonstrated using measurement instrumentation employing a CISPR quasi-peak detector. Above 1000 Mb, compliance with the emission limits in §15.209 shall be demonstrated based on the average value of the measured emissions. The provisions in §15.35 apply to these measurements.



3.3.7.3 Test Procedure for Radiated Spurious Emission

- 1. The EUT is placed on a non-conductive table. For emission measurements at or below 1 GHz, the table height is 80 cm. For emission measurements above 1 GHz, the table height is 1.5 m. The table was rotated 360 degrees to determine the position of the highest radiation.
- 2. During performing radiated emission below 1 GHz, the EUT was set 3 meters away from the interference receiving antenna, which was mounted on the top of a variable-height antenna tower. During performing radiated emission above 1 GHz, the EUT was set 1 or 3 meter away from the interference-receiving antenna.
- 3. For measurements above 1 GHz absorbers are placed on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1 GHz, the absorbers are removed.
- 4. The antenna is a Broadband antenna, and its height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- 5. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters and the table was turned from 0 degrees to 360 degrees to find the maximum reading.
- 6. The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- 7. If the emission level of the EUT in peak mode was 10 dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10 dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.

Measurement Instrument Setting

- 1. Frequency Range: Below 1 GHz RBW = 100 or 120 KHz, VBW = 3 x RBW, Detector = Peak or Quasi Peak
- 2. Frequency Range: Above 1 GHz

Peak Measurement

RBW = 1 MHz, VBW = 3 MHz, Detector = Peak, Sweep time = Auto, Trace = Max hold until the trace stabilizes

Average Measurement

RBW = 1 Mb, VBW \geq 1/T(where, T=pulse width in second), Detector = Peak, Sweep Time = Auto, Trace = Max hold until the trace stabilizes



3.3.7.4 Test Procedure for Conducted Spurious Emission

- 1. The transmitter output was connected to the spectrum analyzer.
- 2. The reference level of the fundamental frequency was measured with the spectrum analyzer using RBW = 100 KHz, VBW = 300 KHz.
- The conducted spurious emission was tested each ranges were set as below. Frequency range: 9 KHz ~ 10 GHz RBW = 100 KHz, VBW = 300 KHz, Sweep Time = Auto, Detector = Peak Trace = Max Hold

LIMIT LINE = 20 dB below of the reference level of above measurement procedure Step 2. (RBW = 100 KHz, VBW = 300 KHz)



3.3.7.5 Test Result

9 KHz ~ 10 GHz Data

Low frequency •

Frequency	Rea	Reading Factor DCCF		Reading		nits	Re	sult	Mai	rgin		
Frequency	Frequency (dB uV/m) (Mz) AV / Peak		Pol.				(dB uV/m)		V/m)	(d	B)	
(Mtz)				(dB)	(dB)	AV / Peak		AV / Peak		AV / Peak		AV /
1 805.58	64.48	67.26	Н	-15.82	N/A	54.0	74.0	48.7	51.4	5.3	22.6	
2 708.11	54.33	57.62	Н	-11.64	N/A	54.0	74.0	42.7	46.0	11.3	28.0	
3 611.00	49.08	53.44	Н	-8.74	N/A	54.0	74.0	40.3	44.7	13.7	29.3	
4 513.81	34.43	43.01	Н	-4.48	N/A	54.0	74.0	30.0	38.5	24.1	35.5	
6 319.21	31.60	39.06	Н	1.45	N/A	54.0	74.0	33.1	40.5	21.0	33.5	

Middle frequency

Frequency	Reading		Factor		ctor DCCF		nits	Re	sult	Mai	rgin			
Frequency	(dB u	(dB uV/m)				I.	Pol.	(dB uV		(dB uV/m)		V/m)	(d	B)
(Mtz)	AV / Peak			(dB)	(dB)	AV / Peak		AV / Peak		AV /	Peak	AV /	Peak	
1 829.48	60.35	64.94	Н	-15.82	N/A	54.0	74.0	44.5	49.1	9.5	24.9			
2 744.35	51.95	56.45	Н	-11.65	N/A	54.0	74.0	40.3	44.8	13.7	29.2			
3 658.92	42.38	47.29	Н	-9.00	N/A	54.0	74.0	33.4	38.3	20.6	35.7			
4 573.79	30.72	39.61	н	-4.97	N/A	54.0	74.0	25.8	34.6	28.3	39.4			
6 403.11	32.40	40.53	Н	1.91	N/A	54.0	74.0	34.3	42.4	19.7	31.6			

High frequency

Frequency		Reading Eactor DCCF		0		nits	Re	sult	Mai	gin	
Frequency	(dB uV/m) AV / Peak		Pol.			DCCF (dB) AV / Peak		(dBu	V/m)	(d	B)
(Mtz)				(dB) (dB)				AV / Peak		AV /	Peak
1 854.58	61.46	65.20	Н	-16.01	N/A	54.0	74.0	45.5	49.2	8.6	24.8
2 781.85	51.46	56.95	н	-11.56	N/A	54.0	74.0	39.9	45.4	14.1	28.6
3 708.94	45.02	50.79	н	-9.02	N/A	54.0	74.0	36.0	41.8	18.0	32.2
4 636.27	35.02	42.87	н	-4.47	N/A	54.0	74.0	30.6	38.4	23.5	35.6
6 490.79	33.35	40.76	н	1.52	N/A	54.0	74.0	34.9	42.3	19.1	31.7

Note 1: The radiated emissions were inverstigated 9 KHz to 10 GHz. And no other spurious and harmonic emissions were found above listed frequencies.

Note 2: DCCF(Duty Cycle Correction Factor)

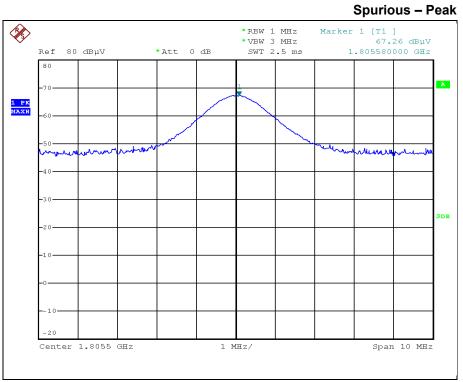
Note 3: Sample Calculation. Margin = Limit – Result / Peak Result = Peak Reading + TF / Average Result = Average Reading + TF

TF = Ant factor + Cable Loss + Filter Loss – Amp Gain

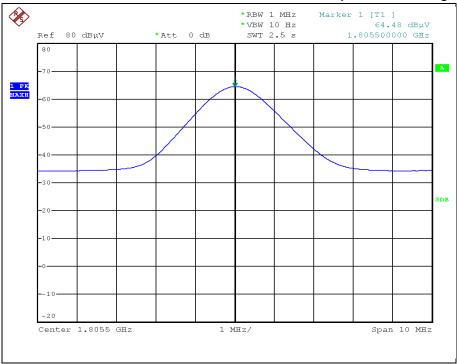


3.3.7.6 Test Plot for Radiated Spurious Emission

• RFID _ Low frequency

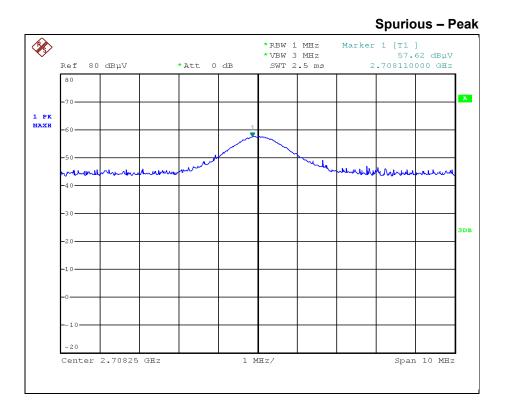


Spurious – Average

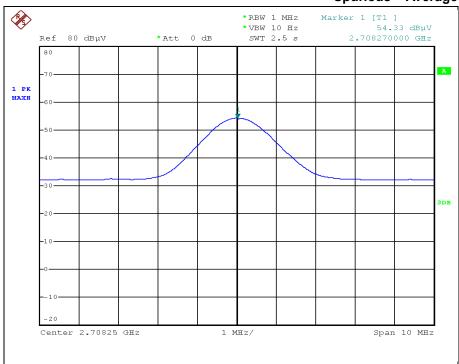


Test Repot No.: NW2112-F005-1

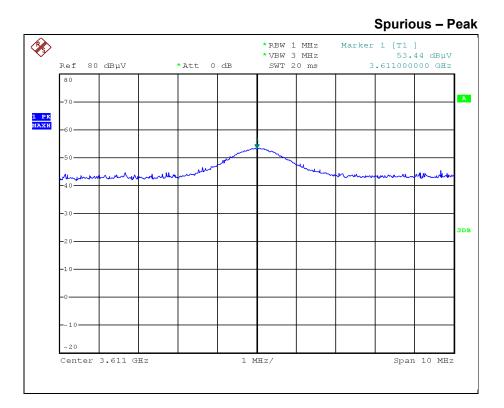




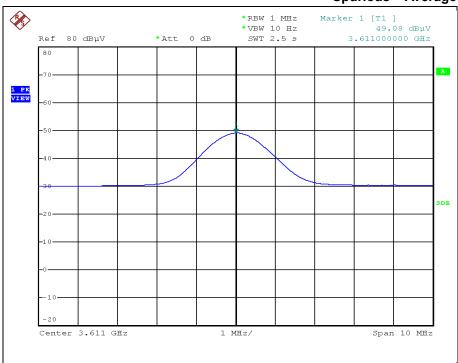
Spurious – Average





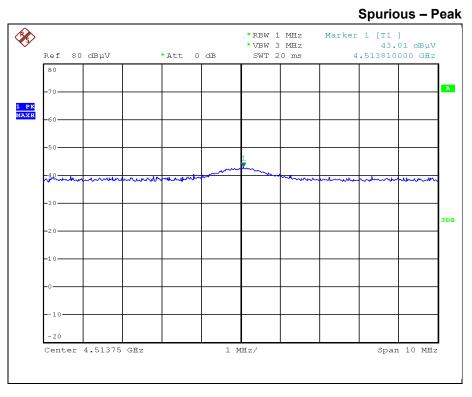


Spurious – Average

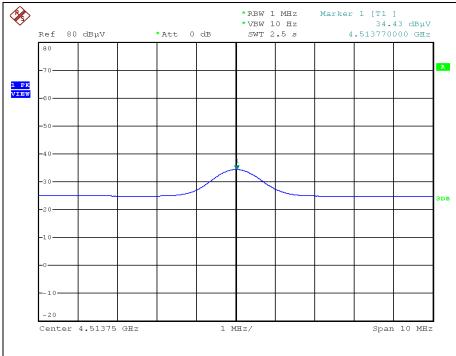


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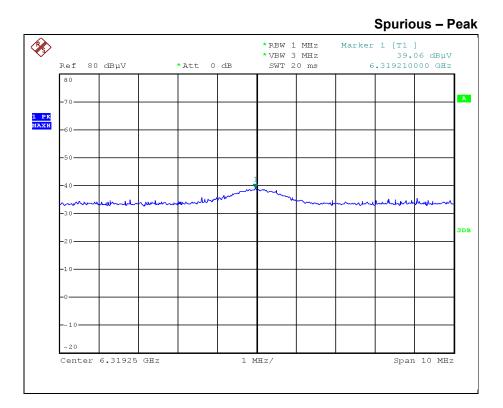




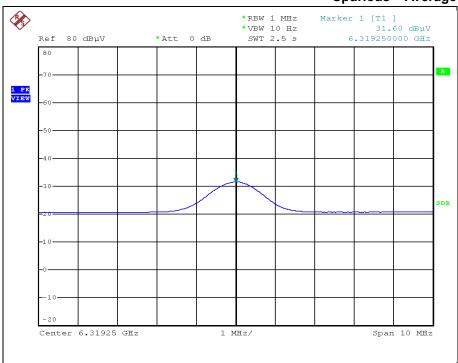
Spurious – Average





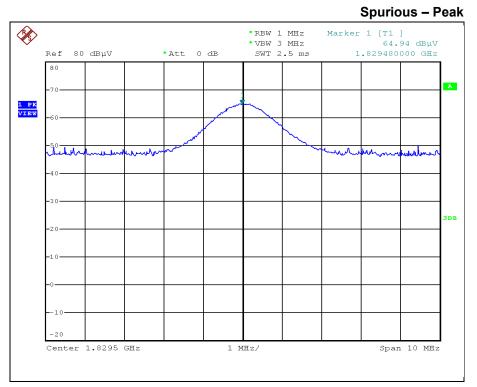


Spurious – Average

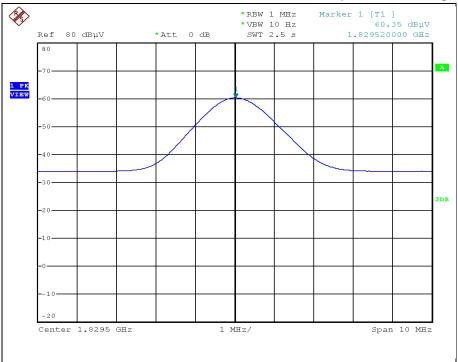




• RFID _ Middle frequency

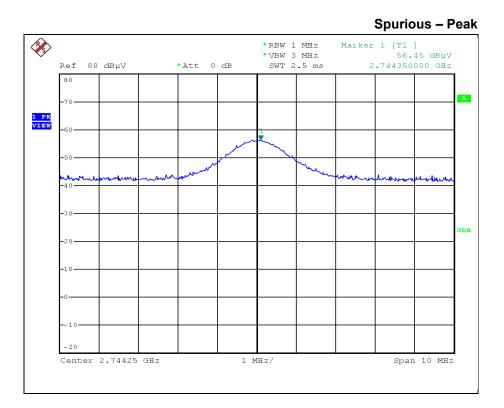


Spurious – Average

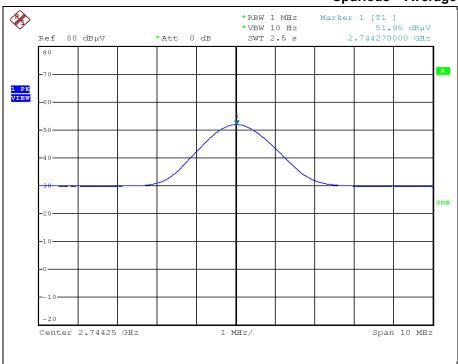


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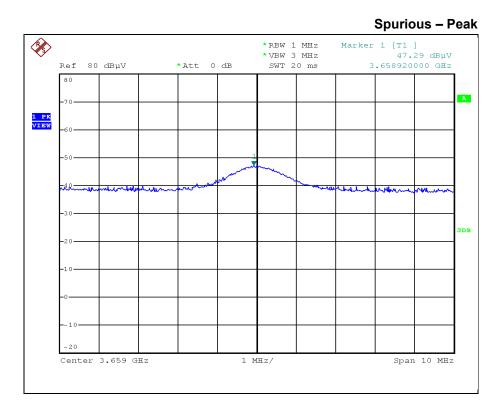


Spurious – Average

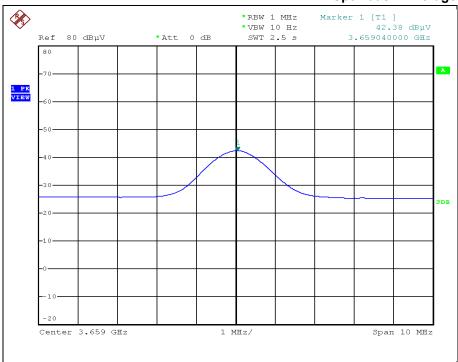


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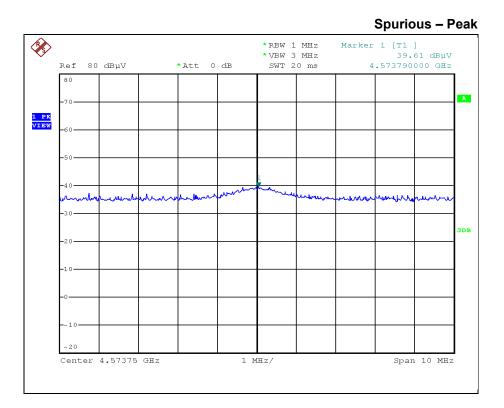




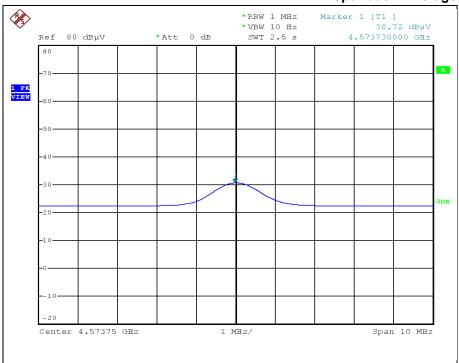
Spurious – Average



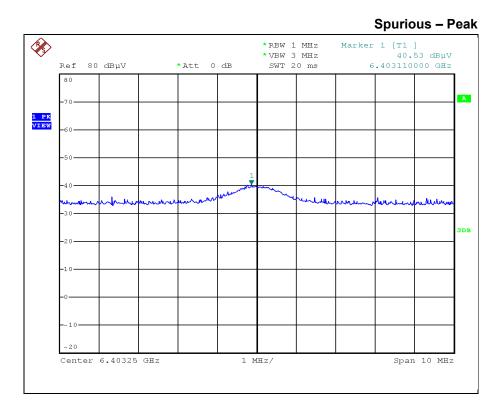




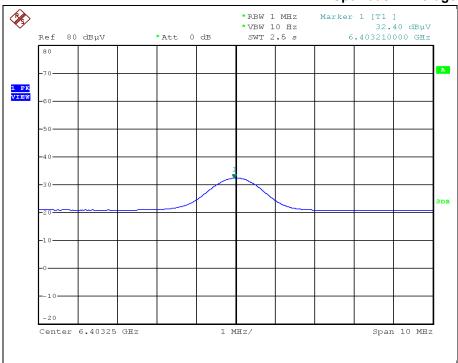
Spurious – Average







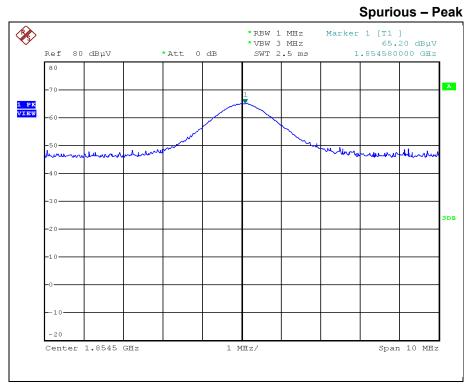
Spurious – Average



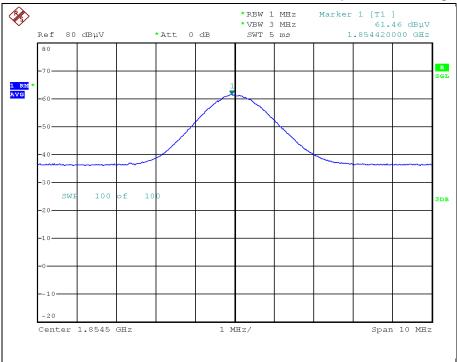
Test Repot No.: NW2112-F005-1



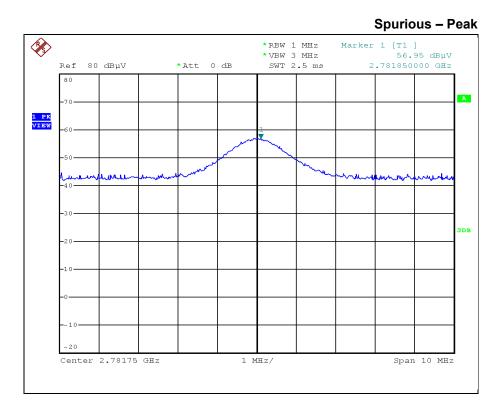
• RFID _ High frequency



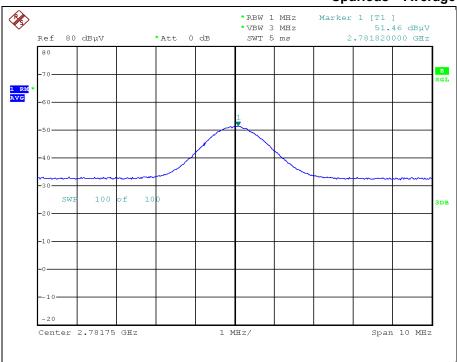
Spurious – Average



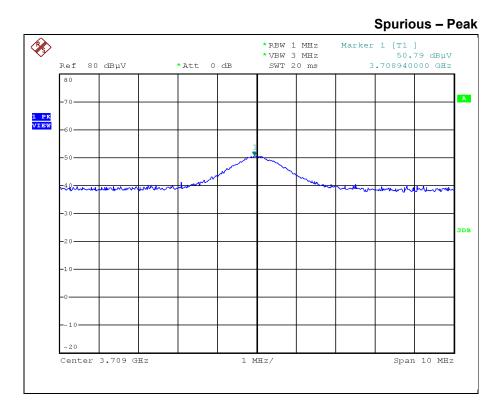




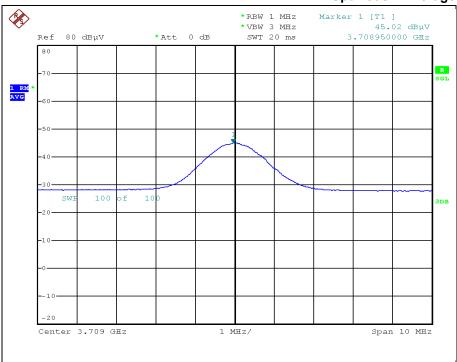
Spurious – Average



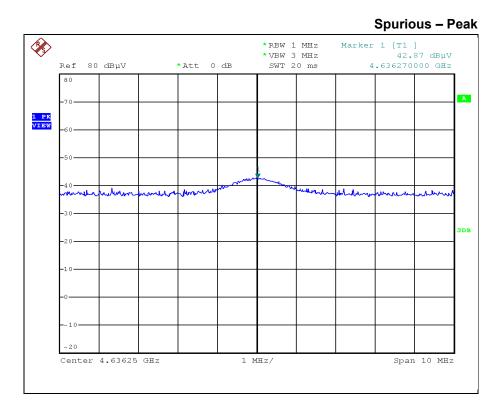




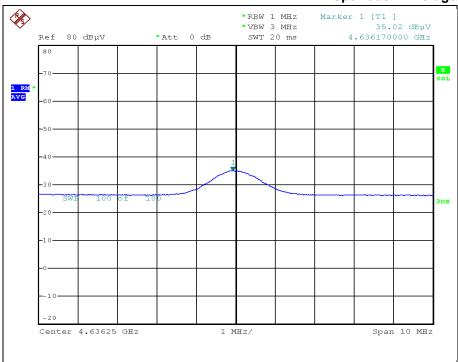
Spurious – Average



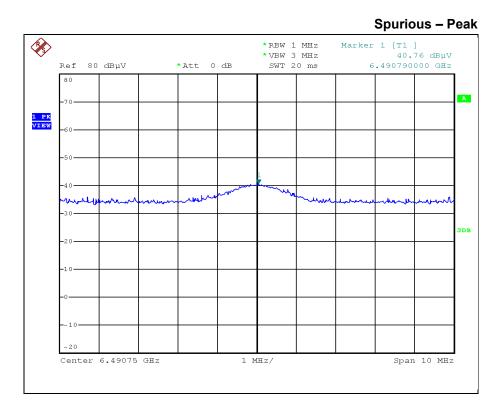




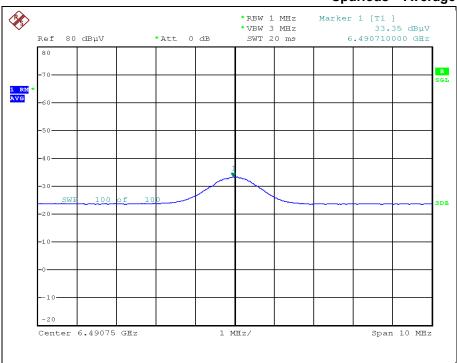
Spurious – Average







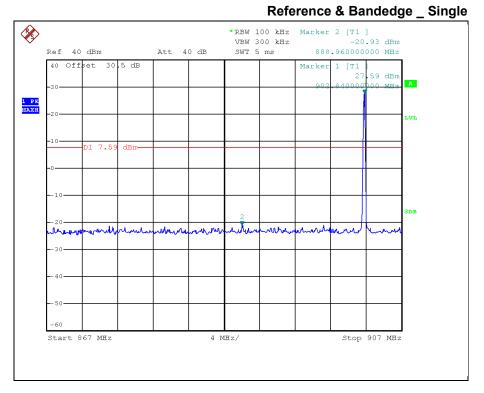
Spurious – Average



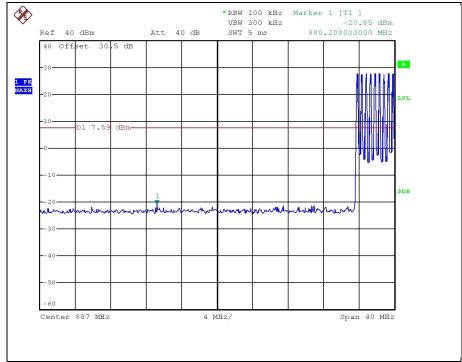


3.3.7.7 Test Plot for Conducted Spurious Emission

• RFID _ Low frequency

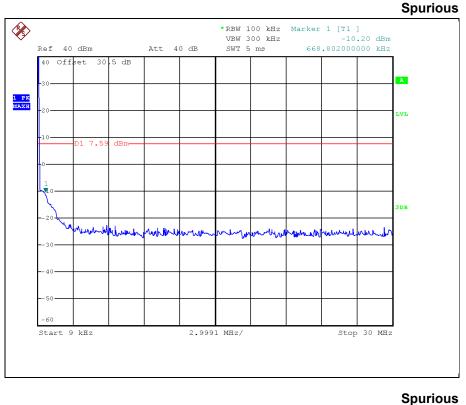


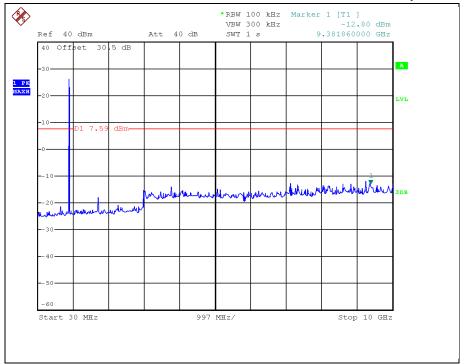
Bandedge _ Hopping



Test Repot No.: NW2112-F005-1

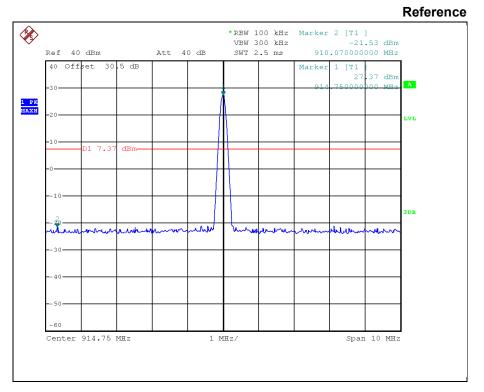




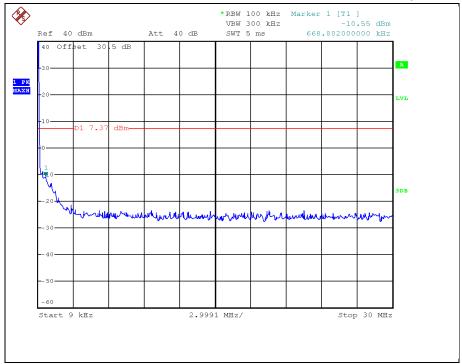




• RFID _ Middle frequency

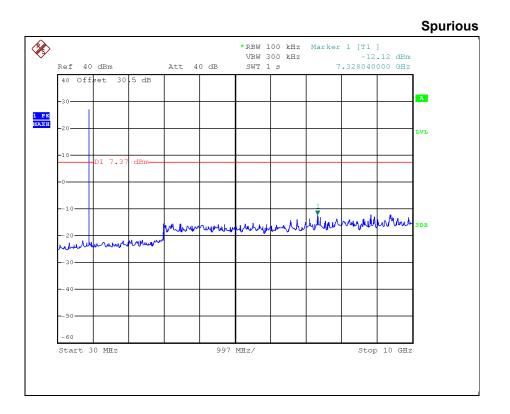


Spurious



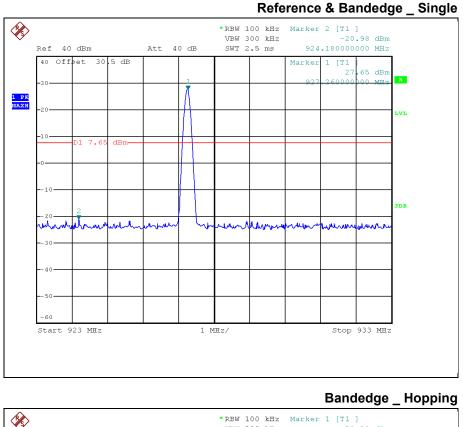
Test Repot No.: NW2112-F005-1

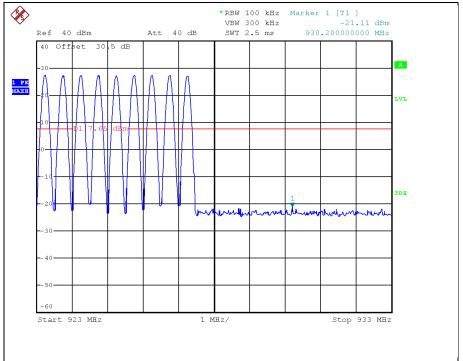






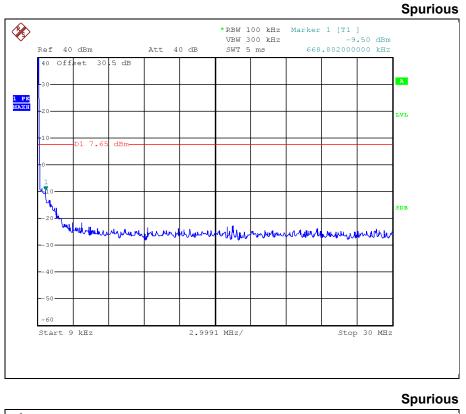
• RFID _ High frequency

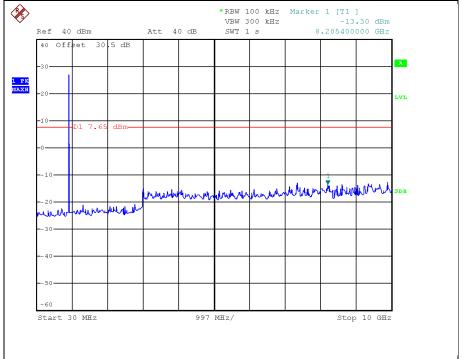




Test Repot No.: NW2112-F005-1









3.3.8 Conducted Emission

3.3.8.1 Test Setup

See test photographs for the actual connections between EUT and support equipment.

3.3.8.2 Limit

According to §15.207(a) for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 KHz to 30 Mb, shall not exceed the limits in the following table, as measured using a 50 uH/50 ohm line impedance stabilization network (LISN).

Compliance with the provision of this paragraph shall on the measurement of the radio frequency voltage between each power line and ground at the power terminal. The lower applies at the boundary between the frequency ranges.

	Conducted Limit (dBuV)		
Frequency Range (Mz)	Quasi-Peak	Average	
0.15 ~ 0.5	66 to 56 *	56 to 46 *	
0.5 ~ 5	56	46	
5 ~ 30	60	50	

* Decreases with the logarithm of the frequency

3.3.8.3 Test Procedure

Conducted emissions from the EUT were measured according to the ANSI C63.10.

- 1. The test procedure is performed in a 6.5 m × 3.5 m × 3.5 m (L × W × H) shielded room. The EUT along with its peripherals were placed on a 1.0 m (W) × 1.5 m (L) and 0.8 m in height wooden table and the EUT was adjusted to maintain a 0.4 meter space from a vertical reference plane.
- 2. The EUT was connected to power mains through a line impedance stabilization network (LISN) which provides 50 ohm coupling impedance for measuring instrument and the chassis ground was bounded to the horizontal ground plane of shielded room.
- 3. All peripherals were connected to the second LISN and the chassis ground also bounded to the horizontal ground plane of shielded room.
- 4. The excess power cable between the EUT and the LISN was bundled. The power cables of peripherals were unbundled. All connecting cables of EUT and peripherals were moved to find the maximum emission.

3.3.8.4 Test Result

Not Applicable

(This product is only using DC power. So, AC conducted emission test has not been performed.)

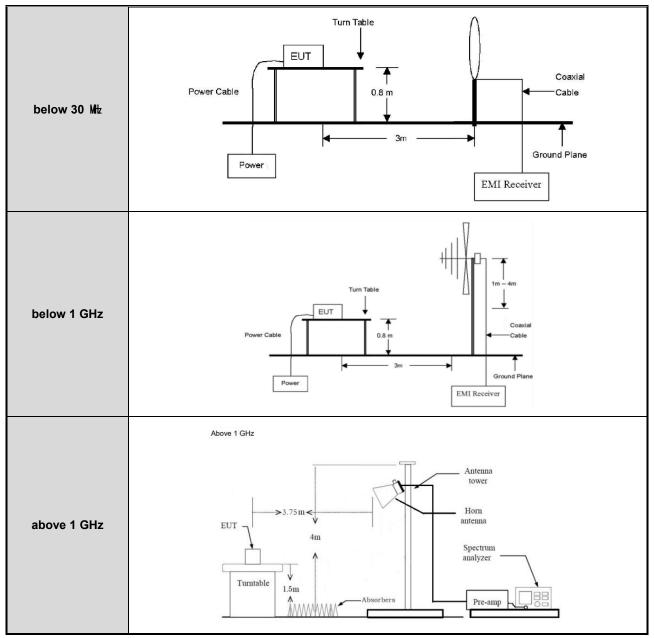


APPENDIX I

TEST SETUP



• Radiated Measurement



• Conducted Measurement

Conducted	EUT	Attenuator Spectrum Analyzer	

Test Repot No.: NW2112-F005-1



APPENDIX II

TEST EQUIPMENT USED FOR TESTS

Test Repot No.: NW2112-F005-1



	Description	Manufacturer	Serial No.	Model No.	Cal. Date	Next Cal. Date
1	SPECTRUM ANALYZER	R&S	100250	FSU26	2021-09-29	2022-09-29
2	SPECTRUM ANALYZER	R&S	100617	FSP40	2021-03-09	2022-03-09
3	Triple Output DC Power Supply	Agilent	MY40038816	E3631A	2021-03-09	2022-03-09
4	TRILOG Broadband Antenna	Schwarzbeck	01029	VULB 9168	2021-05-11	2023-05-11
5	LOOP-ANTENNA	Schwarzbeck	00124	FMZB1519 B	2021-06-01	2023-06-01
6	Double Ridged Broadband Horn Antenna	Schwarzbeck	02087	BBHA 9120D	2021-06-02	2022-06-02
7	ATTENUATOR	Agilent	08259	8493C	2021-03-10	2022-03-10
8	High Pass Filter	Mini-Circuits	1745	VHF-1500+	2021-03-09	2022-03-09
9	ATTENUATOR	Weinschel	none	WA41/12-30-12	2021-03-09	2022-03-09
10	Amplifier	TESTEK	190007-L	TK-PA18H	2021-07-27	2022-07-27



APPENDIX III

UNCERTAINTY



Measurement Item	Expanded Uncertainty U = <i>k</i> Uc (<i>k</i> =2)		
Conducted RF power	0.40 dB		
Conducted Spurious Emissions	0.40 dB		
Radiated Spurious Emissions	5.16 dB		
Conducted Emissions	3.68 dB		